



STS8200 AXE-PLUS

Make Testing More Valuable

Key Features

- Based on STS8200 analog IC resources with static capability of 2000V/1000A and dynamic of 1200V/12000A
- High power DC and AC modules in test head close to DUT for direct-dock
- Dynamic capabilities for switching, short circuit current, RBSOA, Qg, I-Latch, multi-pulse
- Supports multi-task and one socket test
- Target devices:
  - Power Discrete
  - IPM
  - Power Module
  - KGD
  - Wafer

Specifications

|           | Resource      | Specification                                                                                                     |
|-----------|---------------|-------------------------------------------------------------------------------------------------------------------|
| Mainframe | FOVI100       | Floating VI source with up to 8 channels per board: $\pm 40V/\pm 1A$ per channel                                  |
|           | FPVI10_PLUS   | Floating VI source with up to 2 channels per board: $\pm 100V/\pm 10A$ per channel                                |
|           | HVI1K         | Floating VI source with 1 channel per board: $\pm 1000V/\pm 10mA$ per channel (stackable to $\pm 2000V$ )         |
|           | DIO2.0_PLUS   | Digital I/O with up to 8 channels per board: 5MHz test rate, 1M vector depth                                      |
|           | QTMU_PLUS     | Time Measurement Unit with up to 4 channels per board: $\pm 25V$ , $\pm 2ns \pm 0.1\%$ of Rd, and 65ps resolution |
|           | QVM           | Floating voltage meter with up to 4 channels per board: $\pm 100V$ , 18-bit 1MSPS/12-bit 10MSPS digitizer         |
|           | CBIT128       | 128 Relay Control bits per board                                                                                  |
| Test Head | AXE-PLUS-CBIT | Relay Control (160 bits), CBIT (128 bits), DIO (8-ch), QVM (4-ch), QTMU (4-ch) for TIB interface                  |
|           | AXE-PLUS-VIS  | Transfer VI FOVI (8-ch), FPVI (2-ch), HVI1K (1-ch) source from standard test box to TIB interface                 |
|           | AXE-INF       | Isolated interface board with 2-ch HVI1K matrix board and power supply                                            |

Note: Information is subject to change without prior notice.

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➤ Specifications

|  | Resource | Specification                                                                                                                    |
|--|----------|----------------------------------------------------------------------------------------------------------------------------------|
|  | AXE-ZMU  | Ciss/Coss/Crss/Rg testing up to 1MHz, with default DC bias of $\pm 40V$ (upgradeable to $\pm 2000V$ )                            |
|  | FGD      | Floating gate driver max. up to 30A, 4 channels;<br>Vgh: 0V to 30V, Vgl: -30V to 0V                                              |
|  | HPU200   | Floating high-power unit with capabilities up to $\pm 30V$ and $\pm 200A$ (pulse), gang-able up to 1000A                         |
|  | DTU3K    | Dynamic test unit supports up to 1200V/1000A for dynamic switching, 1200V/3000A for short circuit current, 2800V for measurement |
|  | DTU12K   | AC Dynamic resource:<br>1200V/12000A short circuit current capability                                                            |
|  | HVDP     | Each board features four channels: $\pm 2800V$ per channel                                                                       |
|  | PIM-INF  | Supports isolated relay power supply of +5V/+12V                                                                                 |

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